

PolarP™ Power MOSFET

IXTR170P10P

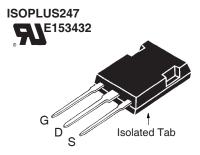
P-Channel Enhancement Mode Avalanche Rated



Symbol	Test Conditions	Maximum Ratings		
V _{DSS}	$T_J = 25^{\circ}C$ to $150^{\circ}C$	-100	V	
\mathbf{V}_{DGR}	$T_J = 25^{\circ}C$ to 150°C, $R_{GS} = 1M\Omega$	-100	V	
V _{GSS}	Continuous	±20	V	
V _{GSM}	Transient	±30	V	
I _{D25}	T _C = 25°C	-100	А	
$I_{\rm DM}$	$T_{\rm C} = 25^{\circ}$ C, Pulse Width Limited by $T_{\rm JM}$	- 510	Α	
I _A	T _C = 25°C	-170	Α	
E _{AS}	T _C = 25°C	3.5	J	
dV/dt	$I_{S} \le I_{DM}, V_{DD} \le V_{DSS}, T_{J} \le 150^{\circ}C$	10	V/ns	
$\overline{\mathbf{P}_{D}}$	T _C = 25°C	312	W	
T		-55 +150	°C	
T _{JM}		150	°C	
T _{stg}		-55 +150	°C	
T,	Maximum Lead Temperature for Soldering	300	°C	
T _{SOLD}	1.6 mm (0.062in.) from Case for 10s	260	°C	
V _{ISOL}	50/60 H _z ,RMS, t= 1min	2500	V~	
M _d	Mounting Force	20120/4.527	N/lb.	
Weight		5	g	

		aracteristic Values Typ. Max.		
BV _{DSS}	$V_{GS} = 0V, I_{D} = -250\mu A$	-100		V
V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -1 \text{mA}$	- 2.0		- 4.0 V
I _{GSS}	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100 nA
I _{DSS}	$V_{DS} = V_{DSS}, V_{GS} = 0V$ $T_{J} =$	125°C		- 50 μA - 250 μA
R _{DS(on)}	$V_{GS} = -10V, I_{D} = -85A, \text{ Note 1}$			15.4 mΩ

 $V_{DSS} = -100V$ $I_{D25} = -100A$ $R_{DS(on)} \le 15.4m\Omega$



G = Gate D = DrainS = Source

Features

- Silicon Chip on Direct-Copper Bond (DCB) Substrate
 - UL Recognized Package
 - Isolated Mounting Surface
 - 2500V Electrical Isolation
- Dynamic dv/dt Rating
- High Current Handling Capability
- Avalanche Rated
- Fast Intrinsic Diode
- The Rugged PolarP™ Process
- Low Q_G
- Low Drain-to-Tab Capacitance
- Low Package Inductance

Advantages

- Easy to Mount
- Space Savings
- High Power Density

Applications

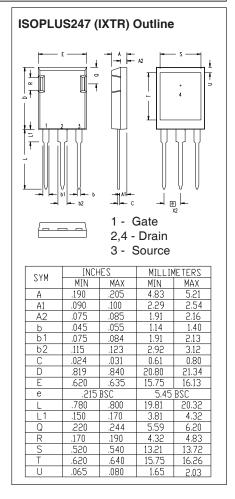
- High-Side Switches
- Push Pull Amplifiers
- DC Choppers
- Automatic Test Equipment
- Current Regulators



Symbol (T _J = 25°C,	Test Conditions Unless Otherwise Specified)	Chara Min.	cteristic Typ.	Values Max.
g _{fs}	$V_{DS} = -10V, I_{D} = -85A, \text{ Note 1}$	35	58	S
C _{iss}			12.6	nF
C _{oss}	$V_{GS} = 0V, V_{DS} = -25V, f = 1MHz$		4190	pF
C _{rss}			930	pF
t _{d(on)}	Resistive Switching Times		32	ns
t _r	$V_{GS} = -10V, V_{DS} = 0.5 \cdot V_{DSS}, I_{D} = -85A$		75	ns
t _{d(off)}	$R_{\rm G} = 10^{\circ}$, $V_{\rm DS} = 0.0^{\circ}$ $V_{\rm DSS}$, $I_{\rm D} = 0.07$		82	ns
t, J	$n_{\rm G} = 152 (\text{External})$		45	ns
$Q_{g(on)}$			240	nC
Q _{gs}	$V_{GS} = -10V, V_{DS} = 0.5 \cdot V_{DSS}, I_{D} = -85A$		45	nC
Q _{gd}			120	nC
R _{thJC}				0.40 °C/W
R _{thCS}			0.15	°C/W

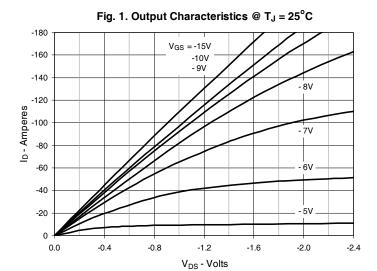
Source-Drain Diode

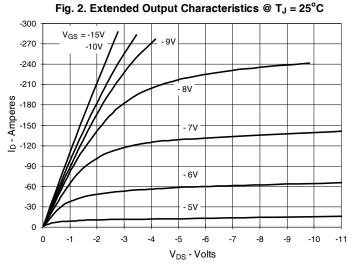
Symbol $(T_J = 25^{\circ}C,$	Test Conditions Unless Otherwise Specified)	Charac Min.	teristic Typ.	Values Max.	
I _s	$V_{GS} = 0V$			-170	Α
I _{SM}	Repetitive, Pulse Width Limited by $T_{_{JM}}$			- 680	Α
V _{SD}	$I_F = -85A, V_{GS} = 0V, Note 1$			- 3.3	V
t _{rr}	$I_{\rm F} = -85A$, $-di/dt = -100A/\mu s$		176		ns
Q _{RM}	$V_{B} = -50V, V_{GS} = 0V$		1.25		μС
I _{RM}	н / 65		-14.2		A

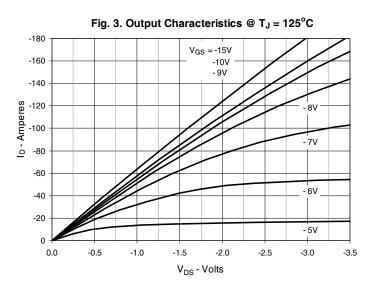


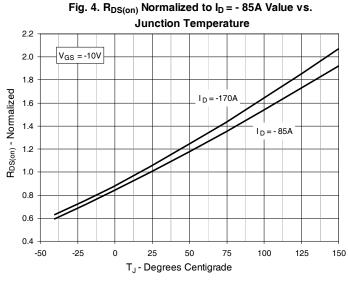
Note 1: Pulse Test, $t \le 300\mu s$; Duty Cycle, $d \le 2\%$.

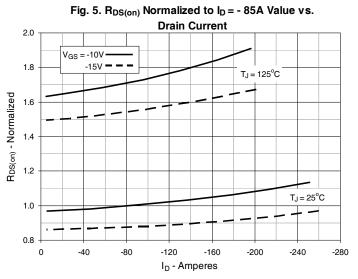


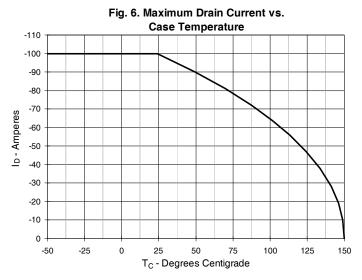




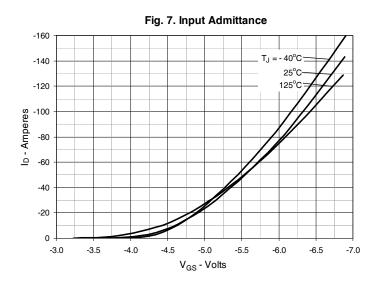


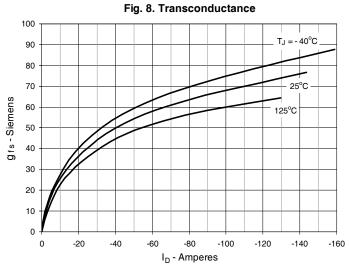


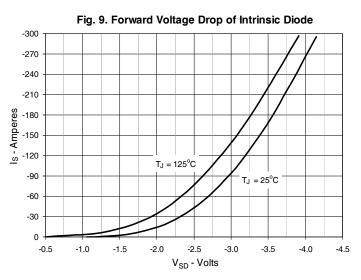


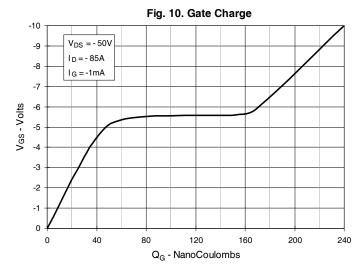


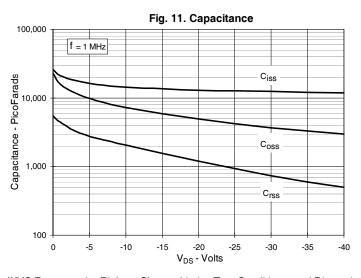


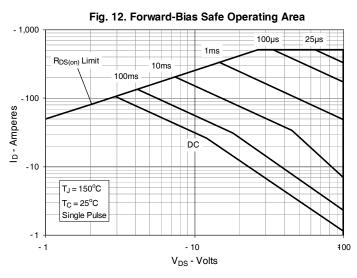












 $\ensuremath{\mathsf{IXYS}}$ Reserves the Right to Change Limits, Test Conditions, and Dimensions.



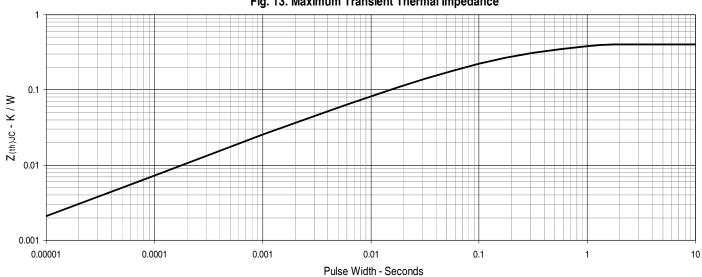


Fig. 13. Maximum Transient Thermal Impedance

